

Enhancing Electronic Performance with a Gallium Oxide Semiconductor

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Abstract: In order to facilitate future communications, the digitalization of society, and the development of applications for artificial intelligence, robust electrical components are absolutely necessary. They should have low energy consumption while achieving ever increasing power densities, which would result in increased operational efficacy. Their footprints should be as tiny as feasible. The purpose of the research is to define the frequency and power limitations for the Gallium Oxide semiconductor, to describe the kind of doping that is suited for Gallium Oxide semiconductors, and to offer a review of defect characterisation using optical and electrical spectroscopic techniques. Because there is no minority carrier storage effect in SBD and its switching loss is quite low, it is beginning to replace p-n junction diodes as a component in power electronic systems as wide bandgap (WBG) semiconductor material technology advances. This is due to the fact that SBD devices based on WBG semiconductors have a lower switching loss. In a-Ga₂O₃ MOSFETs, sluggish trapping and detrapping as well as the associated threshold voltage variations are regularly seen. This makes it anything but a simple problem to solve. A mapping of the interface states as well as its optimization is essential for each potentially promising dielectric material. Additionally, typical stability studies, such as Positive Bias Temperature Instability, must also be performed (PBTI).

Keywords: Semiconductor, Gallium oxide, electronics, wide bandgap

1. Introduction

For future communications, digital transformation of society, and AI applications, powerful electrical components are required. In order to be as efficient as feasible, they should have the smallest possible footprint and use the least amount of energy possible. Therefore, scientists throughout the globe are attempting to find materials and components that may match these criteria. Research conducted by the FBH has made a significant advance in transistors using gallium oxide (beta-Ga₂O₃). With a high breakdown voltage and good current conductivity, beta-Ga₂O₃-MOSFETs are a new generation of metal-oxide-semiconductor field-effect transistors (Higashiwaki et al., 2017). This breakthrough technology achieves performance near to the theoretical material limit of gallium oxide, with a breakdown voltage as low as 1.8 kilovolts and a record power merit figure as high as 155 megawatts per square centimetre. The breakdown field strengths attained are much greater than those of

proven wide bandgap semiconductors like silicon carbide or gallium nitride.

Gallium oxide (Ga₂O₃), a semiconductor with a wide bandgap, may be built into nanometre-scale structures to allow electrons to flow faster inside the structure and increase the efficiency of future high-power devices. Materials used in electrical devices must have a "high electron mobility" so that electrons may travel freely through an electric field. To enhance their performance, many semiconductors are doped with additional elements, however dopants can scatter electrons, reducing the material's ability to conduct electricity (Higashiwaki and Jessen., 2018). Researchers have used modulation doping, a commonly used approach for achieving high mobility but one that had never been used to gallium oxide, to tackle this issue.

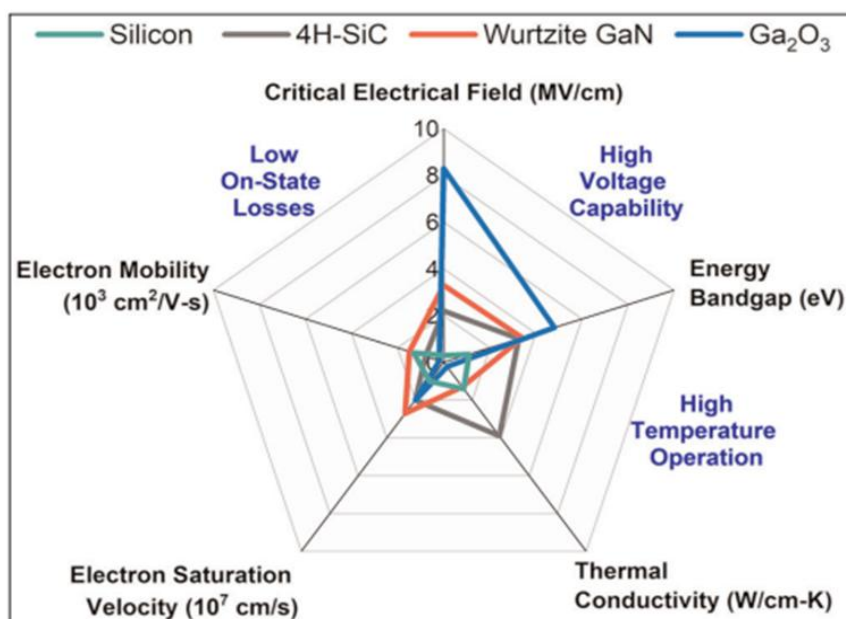


Figure 1: Schematic depicting essential semiconductor power material qualities

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1.1 Background

The Gallium Oxide in Semiconductor Market is expected to increase at a CAGR of 66.9 percent from 2021 to 2030, with a market value of \$8.7 million in 2020. Alkali-soluble gallium sesquioxide (Ga_2O_3), commonly known as gallium oxide, has the chemical formula Ga_2O_3 . In contrast, this chemical molecule is both thermally stable and water insoluble. Additional advantages include an almost 4-electron-volt band gap, which allows manufacturers to reduce the thickness of their devices while maintaining the same voltage (Wellman., 2017). Thinner electrical devices are more efficient because of their reduced resistance. The gallium oxide semiconductor industry is predicted to benefit from the chemical's high efficiency.

Gallium Oxide's distinctive qualities, such as high critical electric-field strength, band gap, and so on, are predicted to be a key driving force in the semiconductor industry's enormous expansion. Due to its greater bandgap energy than gallium nitride and silicon carbide, gallium oxide power electronics outperform its rivals. The energy needed to move an electron from a nonconducting to a conducting state is referred to as the bandgap (Zhou et al., 2019). It is feasible to utilise a smaller device for the same voltage with a bigger bandgap, allowing for more flexibility. When it comes to making devices slimmer, this is critical since it reduces their resistance, making them more efficient.

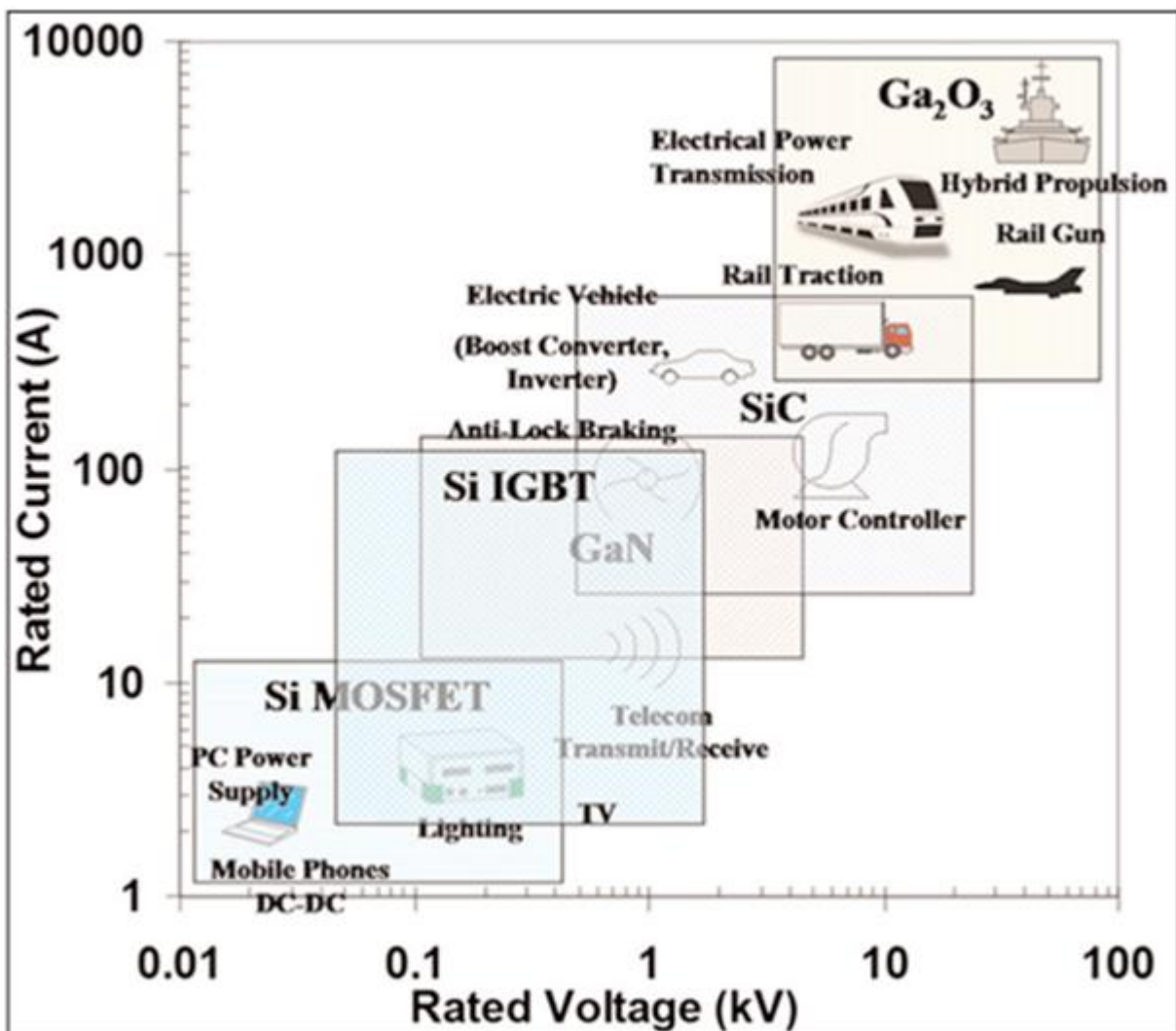


Figure 2: Current and voltage requirements for power electronics based on silicon, silicon carbide, gallium nitride, and gallium nitride

The device's design has been improved, and the diode chip has been made thinner by engineers. A sapphire substrate is used to generate the gallium oxide crystal. The most cost-effective material to utilise is sapphire, which is readily available owing to its application in the production of light-emitting diodes. Using a nonreactive "carrier gas," a mist of particles is sucked into an enclosed chamber to create

gallium oxide devices (Hao., 2019). Gallium oxide coating is formed when metal compounds in the mist react with the heated substrate. As a result of the chamber never having to be totally emptied, the whole process may be completed fast, which also reduces the cost. After their commercialization and advantages are widely publicised, gallium oxide semiconductors have the potential to be industry leaders.

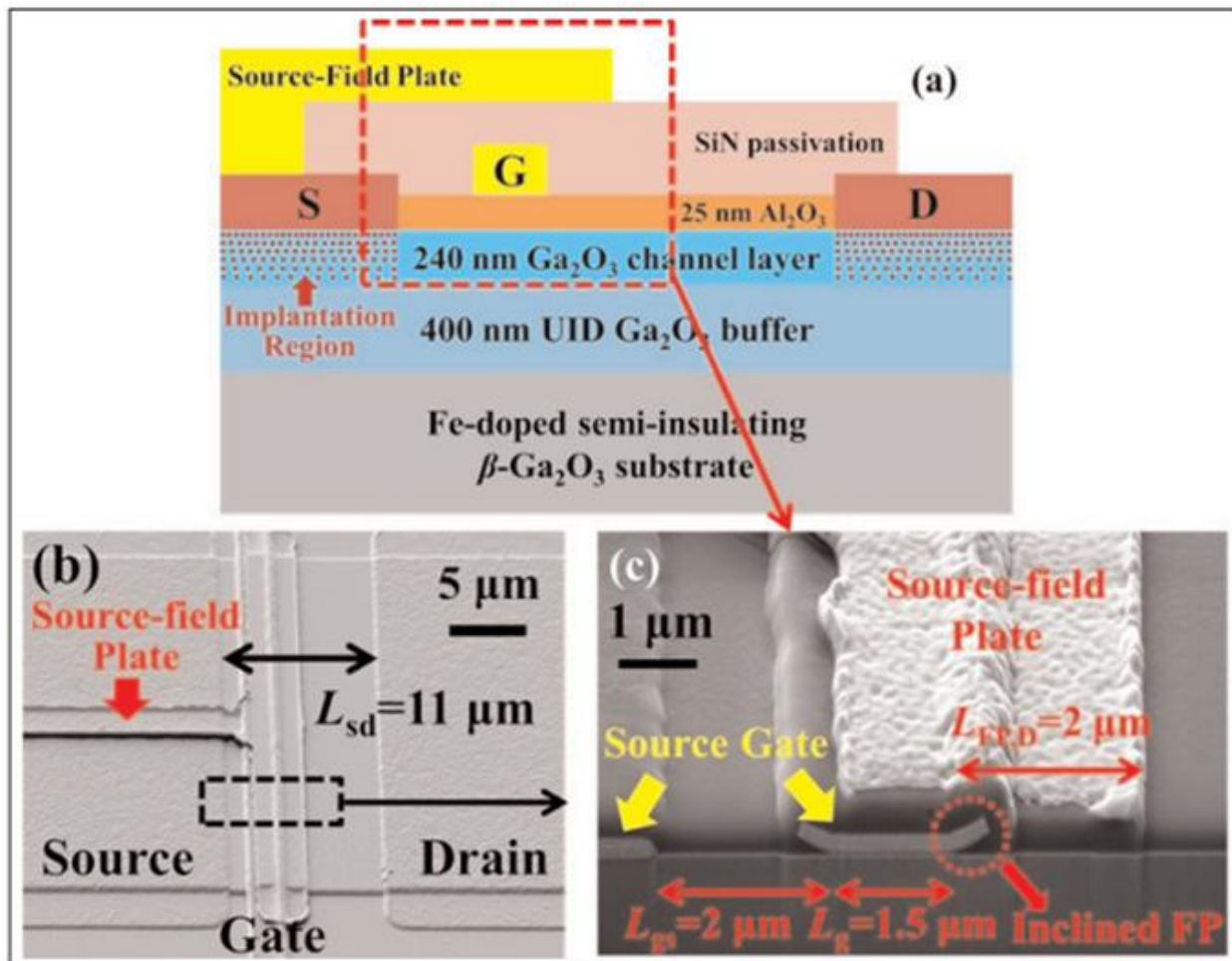


Figure 3: (a) amorphous Ga₂O₃ MOSFET cross section schematic, and scanning electron microscopy pictures of the (b) surfaces and (c) cross-sectional area

2. Literature Reviews

β -Gallium oxide power electronics

In order to realise the full potential of a new semiconductor technology, the community as a whole will have to work together to overcome the technical limits that are restricting performance. Gallium oxide's favourable inherent material characteristics make it an attractive candidate for usage in power electronics as a key application area (Green et al., 2022). Gallium oxide is intended to provide high performance at minimal cost. There are 15 major issues covered in this Roadmap, all of which have been emphasised a high group of researchers in the gallium oxide field. These issues must be resolved if we are to increase the performance of today's most sophisticated devices and create commercially viable microelectronic systems based on the most current semiconductor architecture.

A plan for the development of gallium oxide semiconductors

An investigation by Yuan et al. has shown that gallium oxide (Ga₂O₃) has emerged as one of the most interesting and promising semiconductor materials for new research. Methods for producing Ga₂O₃, material properties, and practical applications are the emphasis of this section. There are alternative wide band gap semiconductors and single crystals that can be made cheaply than -Ga₂O₃-containing single crystals or epitaxial growth. A spike in the use of

Ga₂O₃-based high-performance semiconductor devices has been attributed to the availability of high-quality single crystals, epitaxial films, and rich material systems (Yuan et al., 2021). Because Ga₂O₃ flaws and interfaces have such a large impact on real-world applications, they are thoroughly studied. There are several uses for Ga₂O₃ materials, but this research focuses on two of the more prevalent ones. In terms of power electronic devices, Ga₂O₃'s high Baliga's figure of merit, strong breakdown electric field, and high operating temperature make it an exciting potential. Optically sensitive detectors may benefit from the extraordinary deep-ultraviolet absorption. End of presentation and discussion of materials and technologies based on Ga₂O₃.

Review of -Ga₂O₃ characteristics, growth methods, and devices

As a consequence of its large band gap, Higashiwaki researchers say that the rapid growth of -gallium oxide (-Ga₂O₃) material and device technologies in this decade has garnered substantial attention. Many technologies have progressed as a result of the -gallium oxide bandgap (-Ga₂O₃) (Higashiwaki., 2022). In light of its very strong breakdown electric field and the availability of large-diameter, high-quality wafers manufactured from melt-grown bulk single crystals, Ga₂O₃ seems to hold a lot of potential for use in power switching devices. This is particularly true given its ease of usage. To begin, the material properties of a- Ga₂O₃ important to electrical

devices are examined. Bulk melt growth is discussed, as well as epitaxial thin-film growth and device processing methods now in use. Diodes and transistors based on Ga₂O₃ Schottky barriers Discussed next are field effect transistors, which include Schottky barrier diodes, with the author's group being the major focus.

Gallium oxide for high-power optical applications

Ga₂O₃ has the potential to be employed in high-power optical systems, according to the conclusions of this study by Deng et al. Gallium oxide has been identified as a newly discovered wide-bandgap transparent conducting oxide (TCO). In this article, the fabrication of Ga₂O₃ nanostructures is described in detail. The harm that can be done by a high-powered laser is shown here in the form of nanostructures (LIDT). In addition, a Ga₂O₃ grating-based electron accelerator has been successfully demonstrated, it has been said farther (Deng et al., 2020). Laser damage threshold and acceleration performance of Ga₂O₃ and sapphire dielectric laser accelerators (DLAs) are studied, which is well-known for sapphire's high breakdown strength. For example, high-power optical devices like DLAs and laser diodes might benefit from higher effective LIDT and performance. Using Ga₂O₃, these results might pave the way for new, high-power photonic applications.

2.1 Research Gap

A wide bandgap semiconductor, Ga₂O₃, and AlGa_{0.5}N, are often used in deep UV photodetectors nowadays. Ga₂O₃ has lately emerged as a better alternative to AlGa_{0.5}N because of its improved UV absorption. There is less of a barrier to doping. Only a few investigations have been done on the production of gallium oxide thin films on flexible substrates. These experiments used amorphous thin films^{23,43}. Thin epitaxial -Ga₂O₃ layers on flexible substrates have been a major challenge to date. An epitaxial -Ga₂O₃ thin film photodetector is reported here to fill this gap in our understanding of deep UV photodetector technology (Reese et al., 2019). The optically active trap states have also been shown to contribute to the devices' long-term photocurrent.

2.2 Research Question

- What are the frequency and power limits of Gallium Oxide semiconductor?
- Which type of doping is suitable for manufacturing Gallium Oxide semiconductors?
- What are the defects of gallium oxide semiconductor?

2.3 Importance of the Study

Because of the diverse preparation techniques used while synthesising gallium oxide nanomaterials by hydrothermal method, their characteristics will be affected in different ways. When it comes to the photocatalytic effectiveness of gallium oxide particles, the microsphere morphologies outperform those with microplates or microrods due to their considerable effect on the particle's characteristics (Battu and Ramana., 2018). There are several variables that may

impact the finished product's overall quality during hydrothermal preparation, and six areas will be discussed in depth below.

2.4 Research Objectives

- To determine the frequency and power limits for Gallium Oxide semiconductor.
- To discuss type of doping suitable for Gallium Oxide semiconductors.
- To provide an overview of defect characterisation by optical and electrical spectroscopic approaches.

2.5 Scope and Limitation

Gallium oxide in semiconductors is expected to reach \$8.7 million in global sales by 2030, expanding at a compound annual growth rate (CAGR) of 66.9%. Gallium sesquioxide (Ga₂O₃) is chemically known as Ga₂O₃. On the other hand, this chemical compound is insoluble in water and thermally stable. To keep the same voltage, manufacturers may reduce the thickness of their devices by approximately four electron-volts. Electrical devices that are thinner and hence have lower resistance are more efficient. Gallium oxide semiconductors are predicted to benefit from the chemical's high efficiency (Mandal, Roy and Singh., 2022). Gallium oxide is predicted to be a key growth driver in the semiconductor industry due to its high critical electric-field strength and big gap between it and neighbouring layers.

In the next years, Gallium's market expansion will be stifled by a scarcity of supply. With China's exports of gallium up 300 percent in 2018 and the application of higher import duties on gallium from China, the USGS says that shipments of gallium metal decreased by roughly 90 percent in 2019. Price reductions of around 7% in 2019 were recorded in China's primary-low grade gallium (99.99 percent pure).

3. Research Methodology

In recent years, Ga₂O₃ single-crystal power devices have received a lot of interest because of their low-cost melting procedures. Even though Ga₂O₃'s n-type doping is well developed, it cannot be used in bipolar devices because it lacks p-type doping. Unipolar devices have a tremendous benefit because of their very wide bandgap. For Ga₂O₃ SBD, breakdown voltage is comparable to that of SiC and GaN SBD, however the drift layer is significantly thinner in Ga₂O₃. Due to the lower drift layer, the device has less parasitic capacitance, and hence a quicker reverse recovery. Ga₂O₃ SBD's most major breakthrough. It has evolved from a basic substrate-based structure to a more complicated substrate and epitaxial film-based structure as a result of epitaxy technology. Terminal structures, such as filed plates and trenches, have been developed as a result of research into electronic manufacturing methods. The Ga₂O₃ SBD might have a positive impact on electrical power systems in the future.

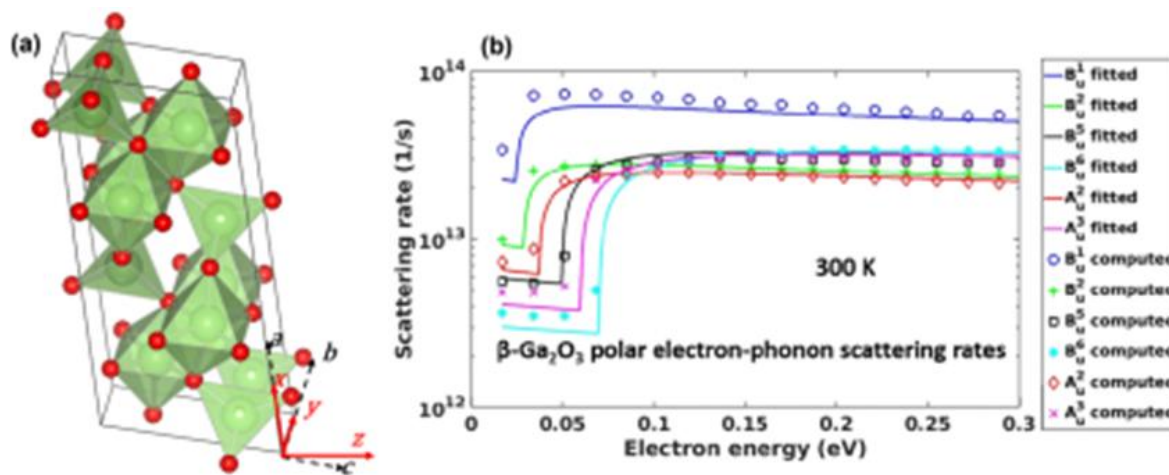


Figure 4: (a) Conventional unit cell of $\beta\text{Ga}_2\text{O}_3$, (b) Six of the twelve IR modes with the greatest POP scattering rates were spherically averaged, revealing the involvement of numerous phonon modes in $-\text{Ga}_2\text{O}_3$

3.1 Research Method & Design

One of the most challenging aspects of studying Ga_2O_3 Schottky junctions is figuring out how to investigate issues like interface states, barrier inhomogeneity, and image force that arise as a result of the system's many moving parts.

3.2 Research Approach

When physical qualities become more discernible and manufacturing techniques improve, gadget performance improves with time. The following are examples of standard Ga_2O_3 SBD research.

High-quality (010) single-crystal Ga_2O_3 was generated using floating zone technique by K. Sasaki and colleagues in Tamura Corporation in 2013. This was studied to see how it affected the device's performance. 150 V is the breakdown voltage. Both devices have an ideality factor of close to 1. According to previous studies, a Schottky barrier of 1.3–1.5 eV exists at the Pt/ $-\text{Ga}_2\text{O}_3$ contact.

4. Analysis of Study

Everything may be utilised horizontally or vertically, or perhaps both. Schottky barrier diodes (SBDs) and photodetectors (PDs) are two of the most often utilised two-terminal devices because of their simplicity of use and economic feasibility. A detailed review of SBDs is necessary to properly grasp how device architecture influences performance, even though SBDs have been extensively covered.

In order to create mobile carriers, a photodiode is required (PD). When a voltage is provided externally or when a

junction has a built-in potential, an electric field is generated. In a M–S–M photodetector with two independent SB connections (like a solar cell), for example, the photocurrent may not be zero with no external bias. Photons with energy greater than the $-\text{Ga}_2\text{O}_3$ band gap may be absorbed in quantities up to 105 cm^{-1} . One nanometer-thick layer of Ga_2O_3 can absorb 90% of the light over the bandgap.

Comparing the output current of lateral SBDs with that of vertical SBDs across a 1- μm width and 5- μm in length drift zone, it's clear that the lateral SBDs create one fifth the output current. The density of the current is assumed to be constant regardless of the direction in which it moves. In addition, a fin-shaped channel with sidewall gates is required for a thick FET channel to successfully gate. This may be used for both horizontal and vertical transistors. In this part, no mention will be made of lateral-topology RF or high-frequency power devices since such material will be covered separately.

Additional vertical Ga_2O_3 devices include SBDs and three more types: Metal–insulator–semiconductor field effect transistors with a fin-shaped channel are known as FinFETs, or vertical trench MOSFETs. The FinFETs reported in Ref. 156 were renamed SITs when transmission electron microscopy showed that their gate length was 50 nm; and (3) current-aperture vertical FETs, which are actually short-gate vertical FETs (CAVETs). 152,157 When it comes to p-type conductivity, Ga_2O_3 is a lot more difficult to work with than $-\text{Ga}_2\text{O}_3$, which is easily obtained. Ga_2O_3 avalanche-capable p–n heterojunctions with built-in potentials greater than 3 eV are still required in the scientific community.

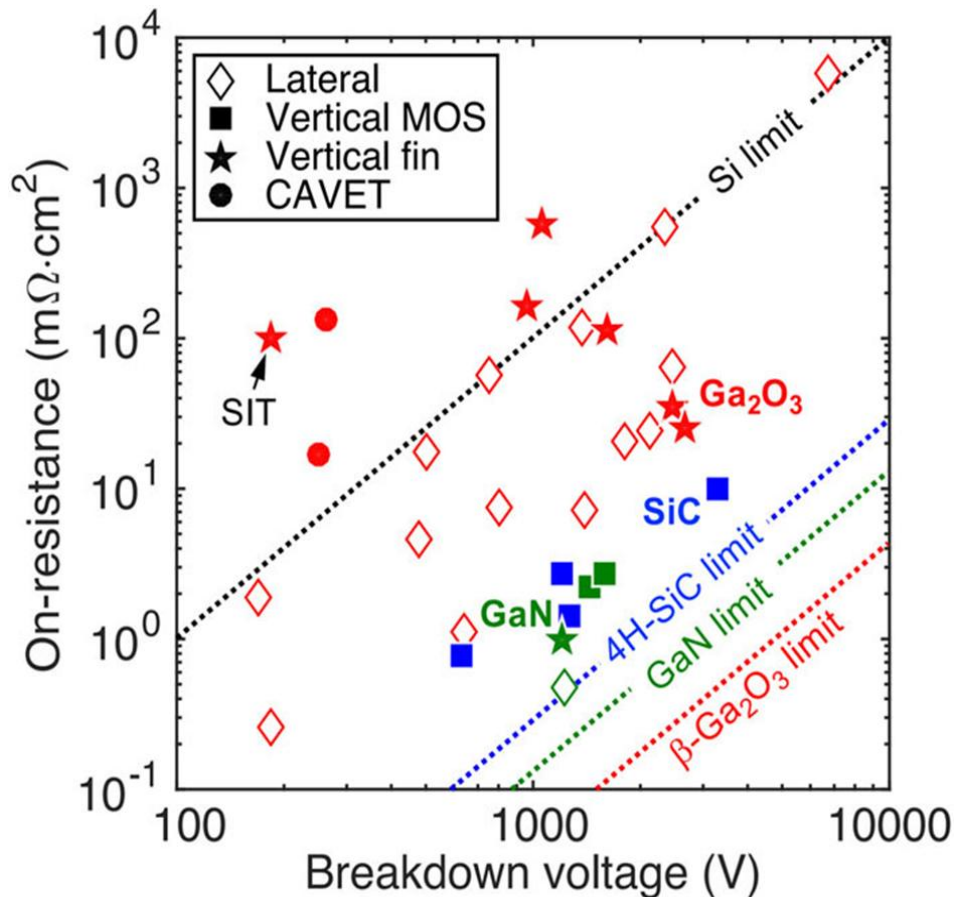


Figure 5: Comparative benchmark plot of the Ga₂O₃ power transistor

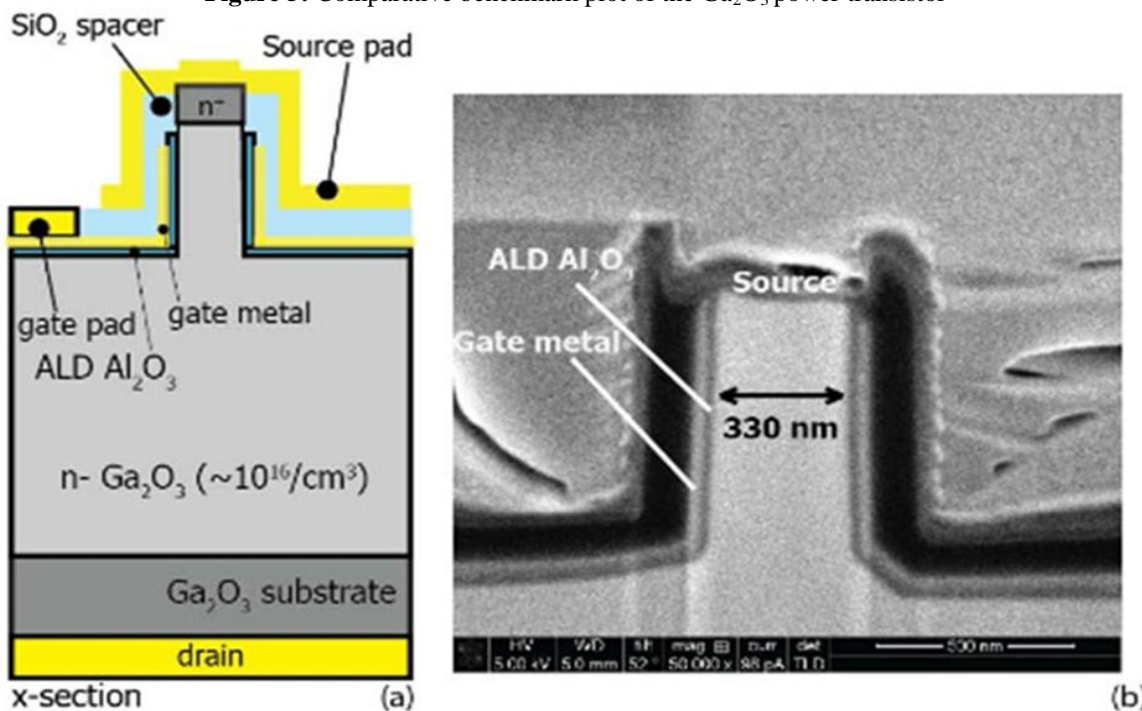


Figure 6: Diagrams of a vertical transistor's channel area, gate, and source electrodes are shown in (a) and (b) respectively

5. Results

Fin channel shape must also take into account the necessity for a lower threshold voltage (V_{th}). The vertical transistors on the other channels are identical.

$V_{th} > 0$ or off operation is recommended for fail-safe operations. When the channel charge is totally depleted, n-

type doping channels may be switched off due to the gate stack's built-in potential. A higher V_{th} demands specialised engineering for work-functions. High effective work functions may be desirable in certain situations for oxidized metals. Greater internal potential will need the use of p-n junction gates. The best epitaxial heterojunction interface is needed for this.

The capacity to regulate and maintain the V_{th} value is critical. A good dielectric–semiconductor contact is required for MIS gates. In $\text{-Ga}_2\text{O}_3$ MOSFETs, delayed trapping and detrapping is not a trivial issue. In addition to standard stability tests such as PBTI, The mapping and adjustment of the interface state is essential for any possibly successful dielectric material.

6. Conclusion

The Ga_2O_3 SBD field is only getting started. Device design is becoming more sophisticated as manufacturing technology advances. Improved single-crystal substrates and epitaxial films have a major impact on device performance. So far, the Ga_2O_3 SBD's development approach has been comparable to the Si SBD and SiC SBD's. Researchers are only beginning to investigate the characteristics of Ga_2O_3 materials. Ga_2O_3 has an ultrawide bandgap of 4.7–4.9eV, which experts think may be further shown through the design of device architectures and a joint effort among scientists.

With its broad bandgap, $\text{-Ga}_2\text{O}_3$ is an excellent replacement for SiC and GaN in power switching and RF devices in the future generation. Worldwide, there will be an increasing need for power switching devices that assist conserve energy in the near future. A new frontier in semiconductor electronics may be opened up by Ga_2O_3 RF FETs operating in harsh environments, such as high temperature or strong radiation. This is a major issue because of the difficulty of Ga_2O_3 to adequately disperse heat. Because there is no p-type material with suitable hole conductivity for Ga_2O_3 devices, the design options are severely limited in this material. Ga_2O_3 devices' limited heat conductivity, particularly in high-power device applications, is another severe problem. $\text{-Ga}_2\text{O}_3$ devices must be aware of these two flaws and endeavour to remedy them in the future.

6.1 Future Scope

More advanced $\text{-Ga}_2\text{O}_3$ FET and diode technologies still face considerable barriers in terms of bulk melt growth, epitaxial thin film growth, and device manufacture. A concern is the use of iridium (Ir) in bulk melt growth and wafer manufacturing as a costly crucible material. Ga_2O_3 bulk wafers in the crucible must be reduced significantly in order to reduce manufacturing costs. Before HVPE and MOCVD epitaxial growth can be considered for mass production, there is a lot of work to be done. There is a lot of interest in the creation and study of p-type doping, as well as the improvement and dependability of n-type doping. Epitaxial growth of $(\text{AlGa})_2\text{O}_3$ and $(\text{InGa})_2\text{O}_3$ heterostructures should be a top focus in the research community. While bulk and epitaxial growth procedures are being developed, the academic community should support basic research into the physics of $\text{-Ga}_2\text{O}_3$. By better understanding how point flaws in Ga_2O_3 function, we may be able to create more dependable devices. New devices with unique capabilities may be built by purposely altering the point of failure.

6.2 Suggestions

In the field of device processing, several essential technologies have yet to be created. The method of ion-implantation doping, one of Ga_2O_3 's biggest advantages, has yet to be developed. Ion implantation necessitates both the creation of novel doping components and the optimization of existing ones. For vertical FETs and diodes, etching is becoming more important. Inductively coupled plasma (ICP) and reactive ion etching (RIE) are often used in the fabrication of Ga_2O_3 devices. We need to come up with a new etching method that causes the least amount of harm. Since the bandgap of $\text{-Ga}_2\text{O}_3$ is more than 4 eV, it is difficult for gate dielectric materials to create substantial barriers at the dielectric/ $\text{-Ga}_2\text{O}_3$ interface. In addition, the quality of the interface, particularly for typically off FETs, must be improved. The inability of $\text{-Ga}_2\text{O}_3$ devices to dissipate heat effectively is a major problem when operating high-power devices. Using a foreign substrate with excellent thermal and electrical conductivities is one of the most effective methods to enhance it.

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